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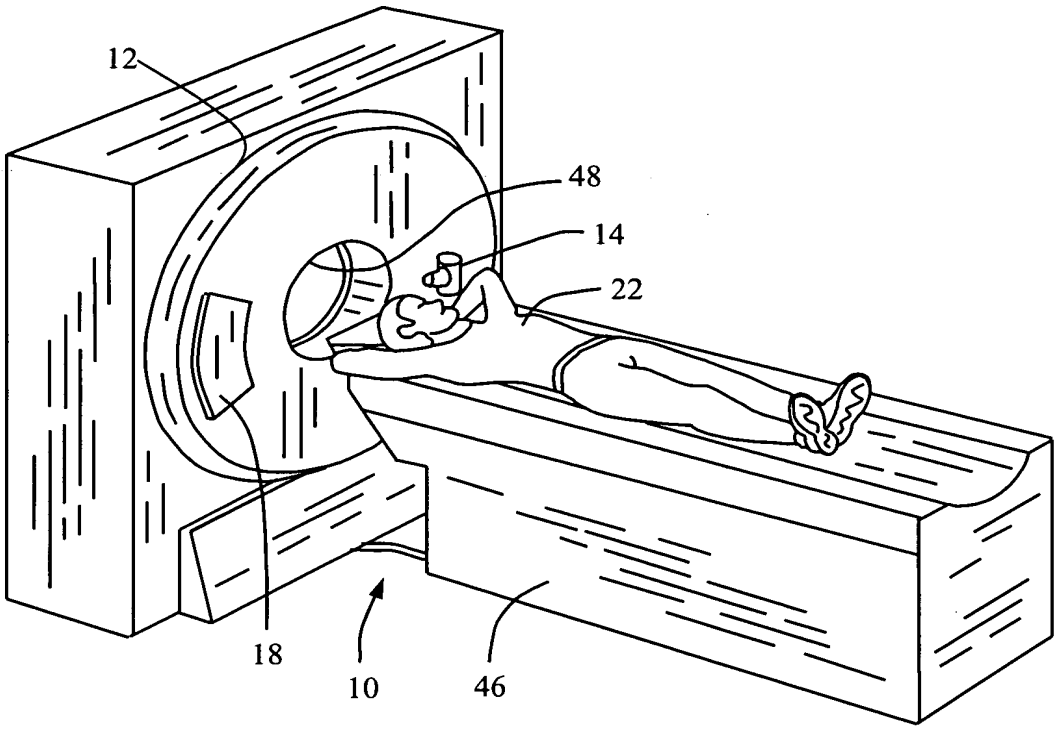

FIG. 1

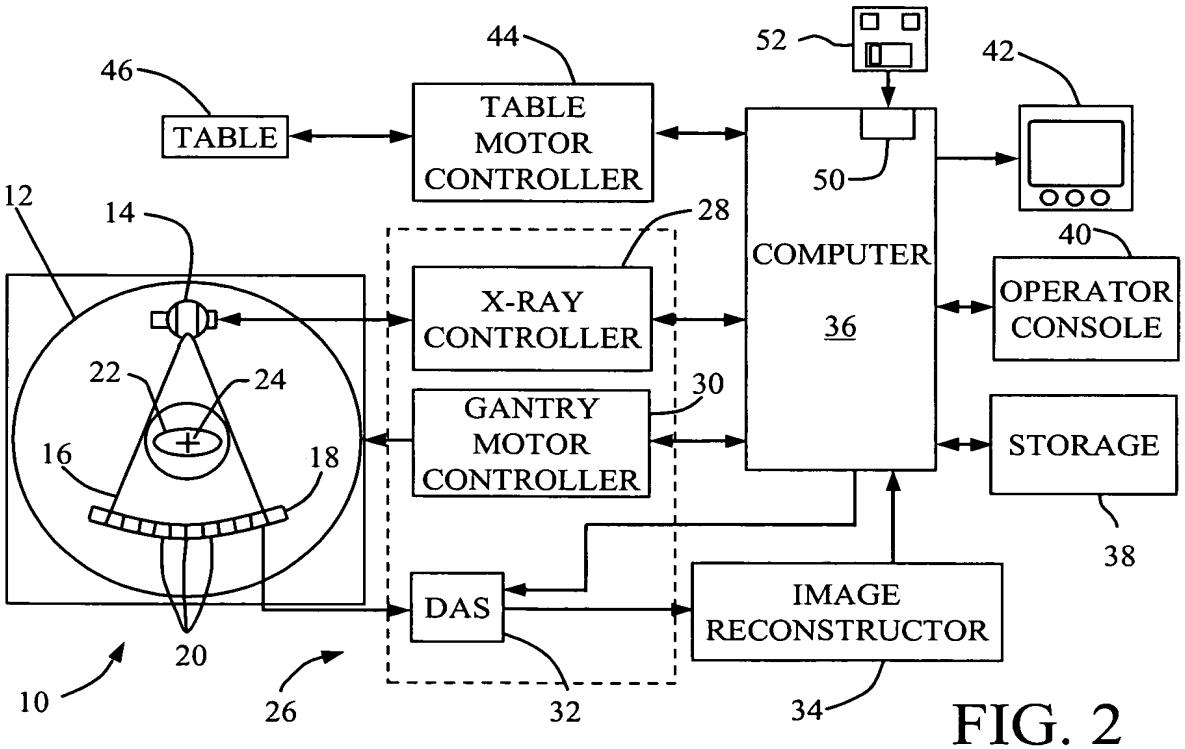

FIG. 2

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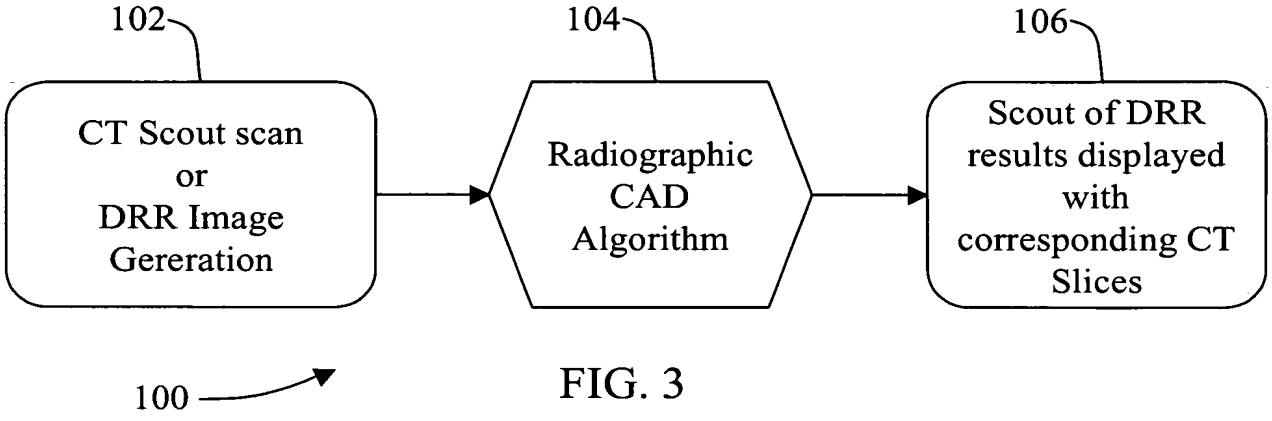

FIG. 3

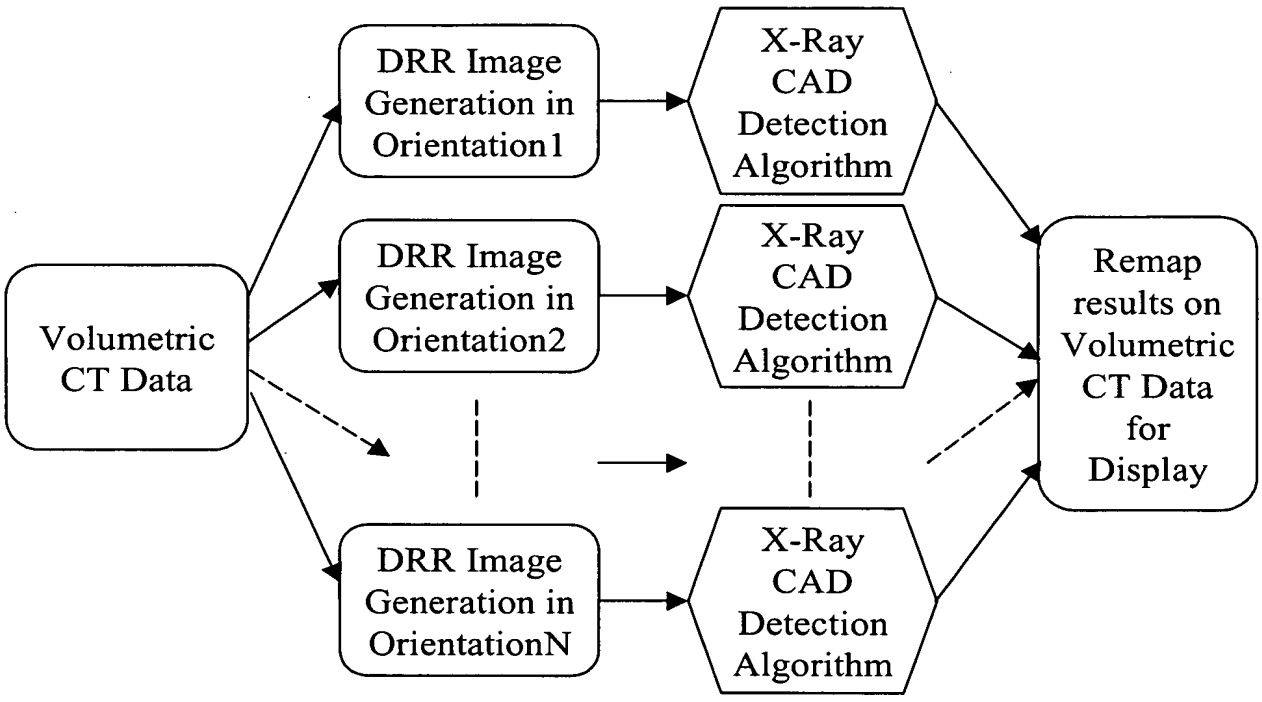

FIG. 4

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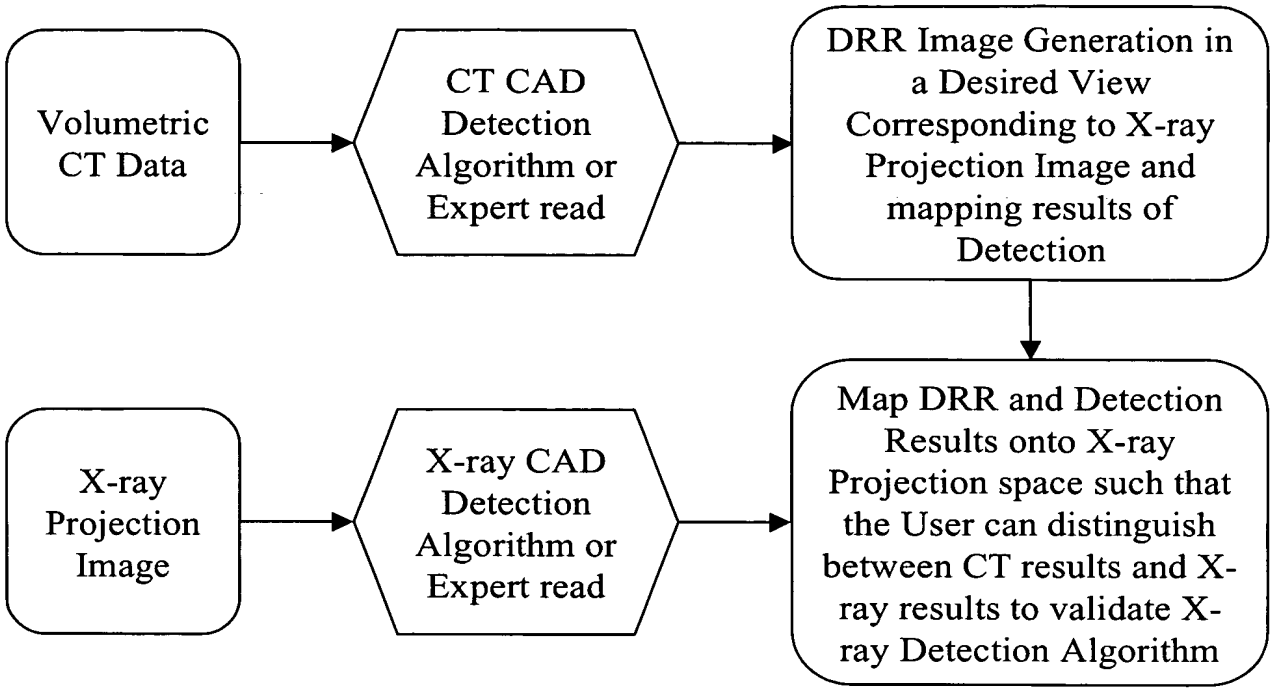

FIG. 5

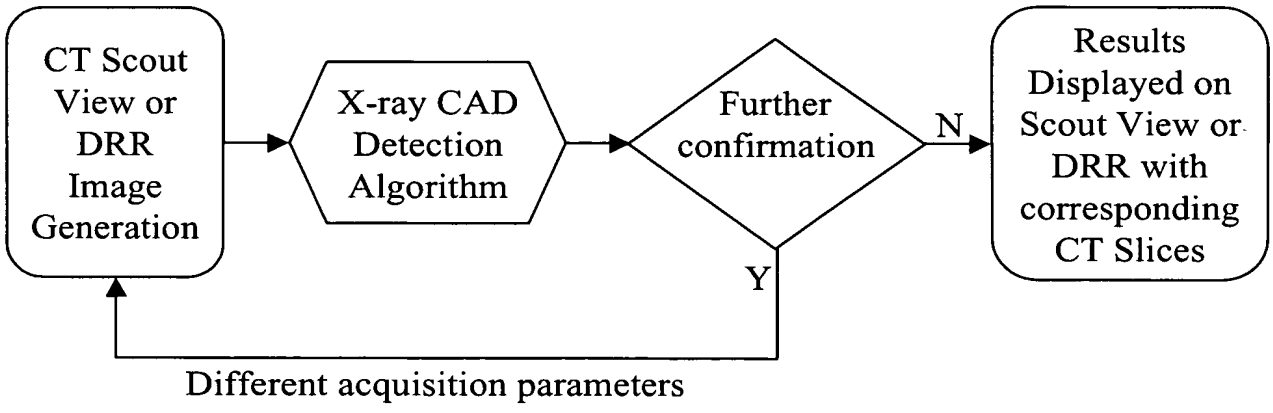

FIG. 6

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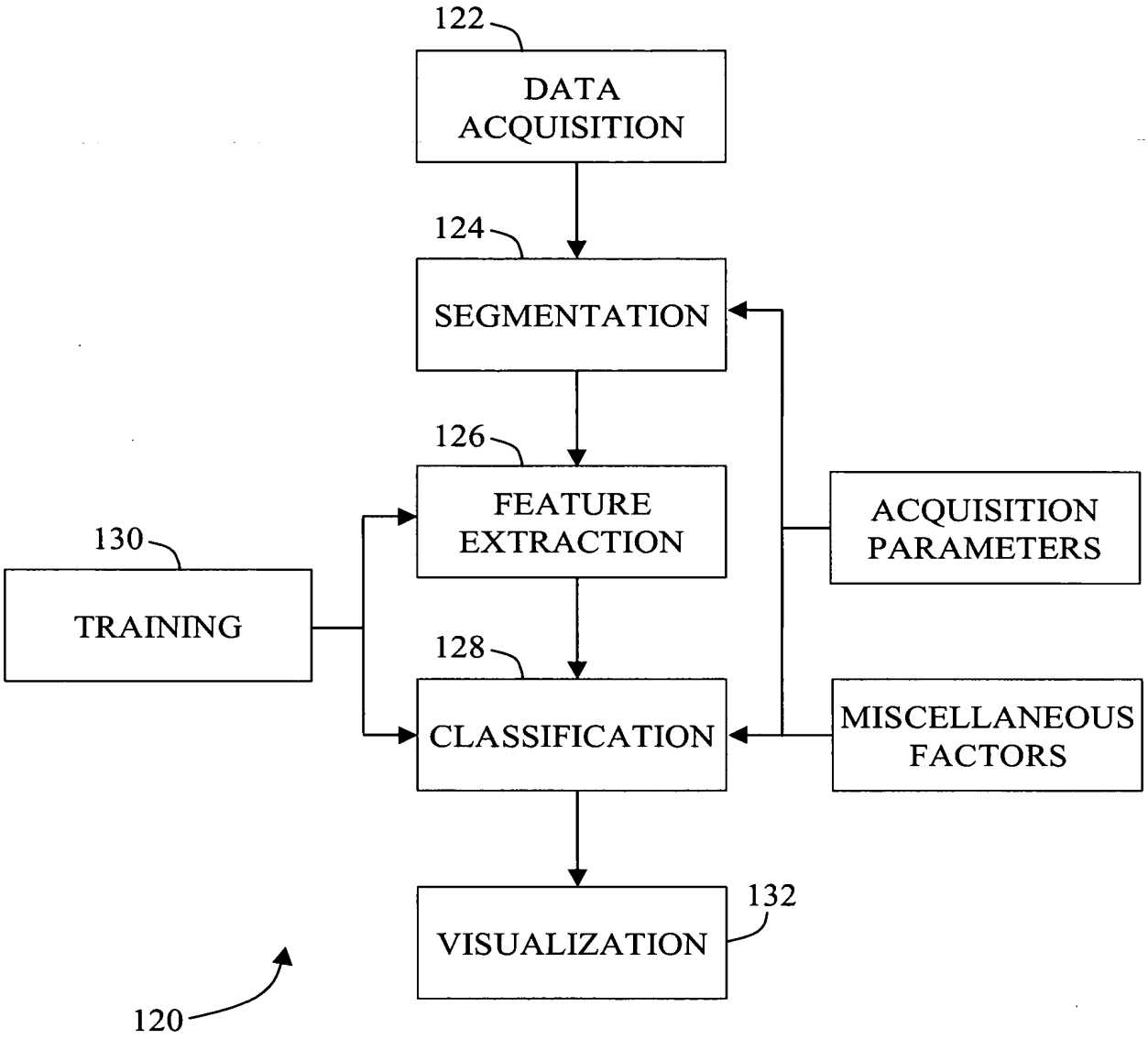

FIG. 7 Schematic of CAD process.

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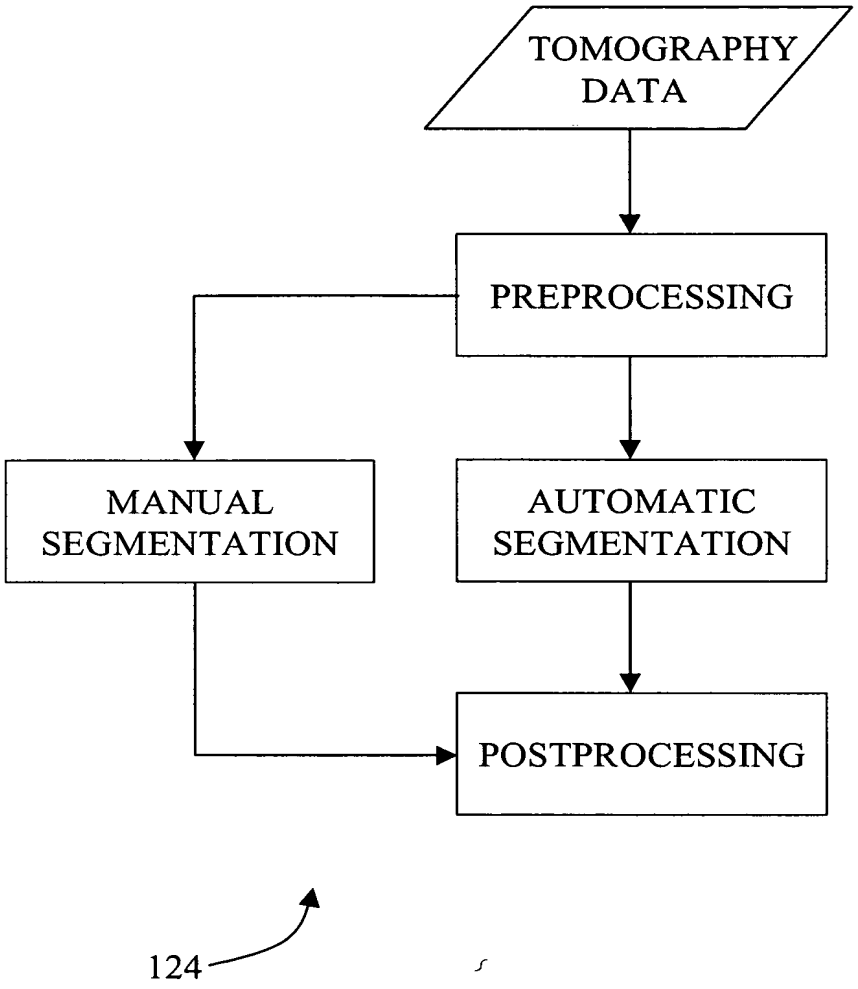

FIG. 8 Segmentation process for data.

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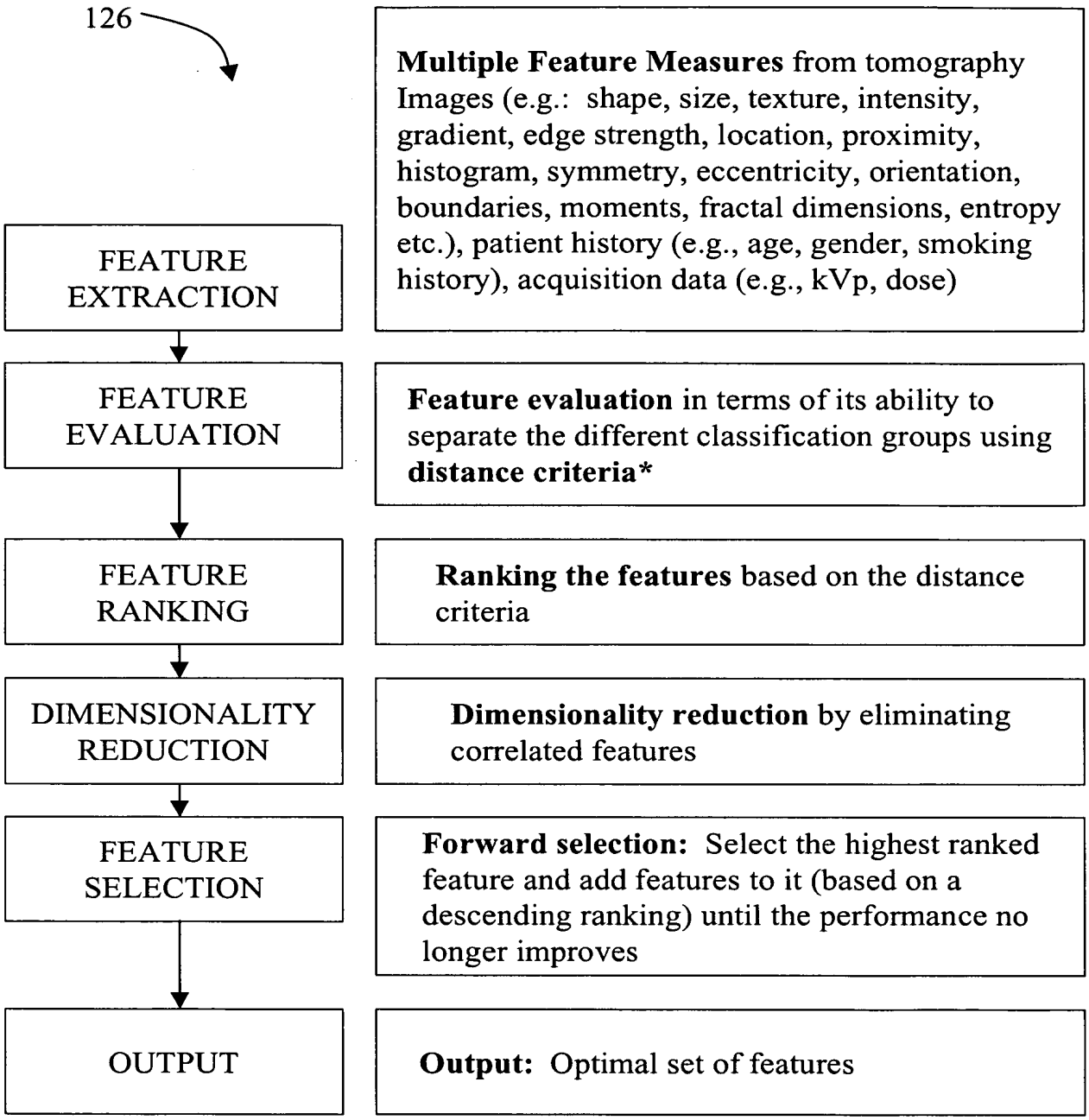

FIG. 9 Feature selection process for data.

*Several different distance criteria can be used: Divergence, Bhattacharya distance, Mahalanobis distance. These techniques are described in standard textbooks including: K. Fukanaga, Introduction to Statistical Pattern Recognition. Academic Press, 2nd ed., 1990.

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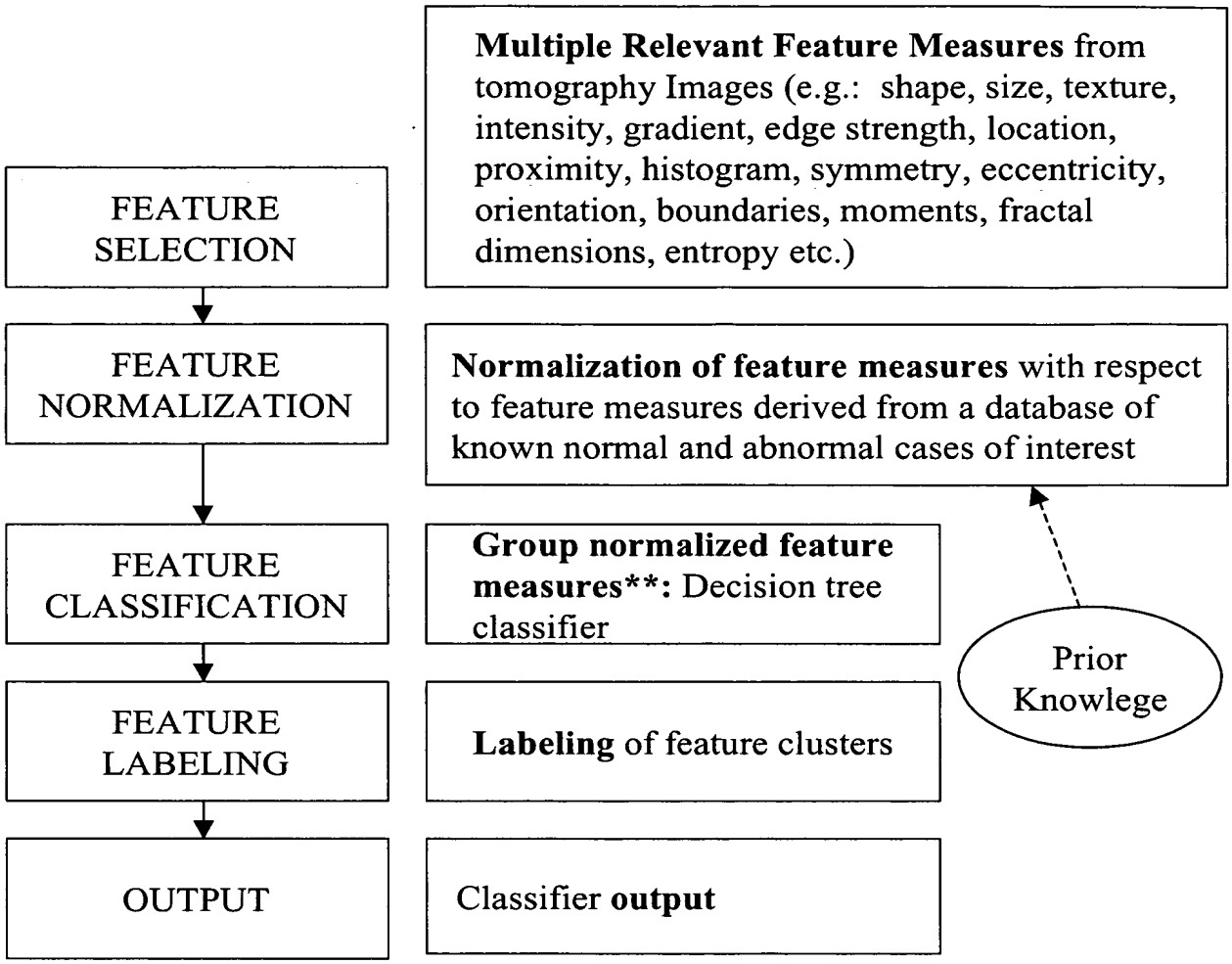

FIG. 10 Feature classification process for tomographic data.

**Several different methods can be used: Decision tree anaylsis, discriminant function analysis, Bayes' minimum-risk method, clustering techniques, similarity measure approach. These techniques are described in standard textbooks including: Fundamentals of digital image processing by Anil K. Jain, Prentice Hall (1988).